

Abstract

A system for testing an integrated circuit, the integrated circuit including: flip-flops connected to a logic block and the test system including circuitry for connecting the flip-flops as a register, circuitry for inhibiting the different elements of the logic block capable of disturbing the sequencing of the register or the propagation of the signals into the logic block, and a control circuit for separately controlling the different inhibiting circuits and the circuitry for connecting the flip-flops as a register.